

AFM and SEM investigations of ion beam synthesized Mg₂Si precipitates in Si substrates

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BSCCO ceramics doped with ferromagnetic manganite phases

Staneva, Anna; Stoyanova-Ivanova, Angelina; **Terzieva, Stanimira**; Shoumarova, Janna; Grigorov, K.; Zaleski, Andrzej; **Mikli, Valdek**; Angelov, Christo; Dimitriev, Yanko Journal of optoelectronics and advanced materials 2009 / 10, p. 1541-1544
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Comparative ellipsometric and ion beam analytical studies on ion beam crystallized silicon implanted with Zn and Pb ions

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Morphology of Y₁Ba₂Cu₃O_z and Y_{0.7}Ba₂Cu₃O_z bulk samples depending on Ca-substitution

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Pb and Bi nanocluster precipitation in high-dose implanted and RTA Si: SEM and RHEED analyses

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The influence of the partial Ca substitution on the microstructure of YBCO tapes

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Use of atomic-force microscopy for characterization of silicon, implated with heavy ions at high doses

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